

# Load Capacitance Measurement

One of the most commonly used crystal oscillation circuit nowadays is Pierce-gate as shown in figure 1. It comprises a simple inverter gate, a feedback resistor  $R_f$ , two external load capacitors  $C_a$  and  $C_b$ , and a crystal  $X1$ .

The equivalent circuit is shown in figure 2. At resonance, the crystal becomes a resistance  $R_L$  in series with an inductance  $L_L$ . The gate amplifier and its associated components form a negative resistance  $-R$  in series with a load capacitance  $C_L$ . According to Barkhausen criteria for oscillation, the reactance of  $L_L$  would be exactly equal but opposite in sign to that of  $C_L$ , and therefore the closed loop reactance becomes zero. In addition, the absolute magnitude of  $-R$  ( $|-R|$ ) must be greater than or equal to  $R_L$  in order to have loop gain greater than or equal to unity. The ratio  $|-R|/R_L$  is called *oscillation allowance*. Higher oscillation allowance provides better safety margin when environment condition changed, such as temperature and humidity.

The equivalent circuit  $C_L$  can be estimated by a simplified equation:

$$C_L = \frac{(C_a + C_{in})(C_b + C_{out})}{C_a + C_{in} + C_b + C_{out}} + C_{stray} \quad (1)$$

where

- $C_{in}$  = internal pin capacitance of the gate input
- $C_{out}$  = internal pin capacitance of the gate output
- $C_{stray}$  = overall stray capacitance of the PCB

The above equation has been simplified with some assumption made, and should be used for rough estimation only. A more precise model would include the transconductance (gm) of the gate inverter, and also the  $C_0$  of the crystal.

Another practical way to find  $C_L$  is by using a crystal network analyzer and a spectrum analyzer. The circuit oscillating frequency  $f_{osc}$  would be picked up by non-contact hi-impedance probe (or antenna), and measured by a high precision spectrum analyzer with frequency accuracy at least 0.1ppm or better. Then the sample crystal would be removed from the PCB and measured with a precise crystal network analyzer. Measure the  $C_L$  at which  $f_L$  equals  $f_{osc}$ . If an automatic crystal network analyzer is used (e.g. KOLINKER KH1800), the  $C_L$ ,  $C_0$ ,  $R_s$  and other crystal parameters could be measured automatically with compliance to IEC60444-11 international standard.

If an automatic crystal network analyzer is unavailable, the crystal parameters could also be measured with a general network analyzer. Please refer to the IEC60444 standard, or search "Direct Impedance Method" from the internet for details.

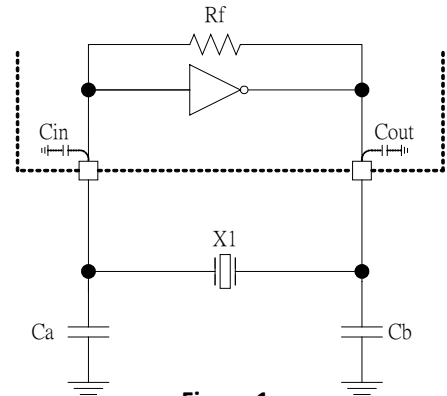


Figure 1

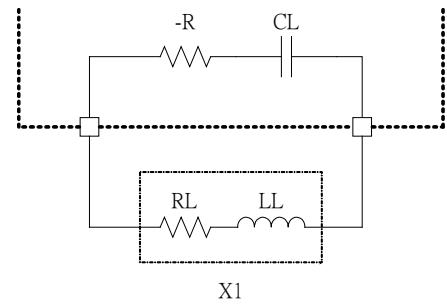


Figure 2